National Standards Authority of Ireland

IRISH STANDARD

I.S. EN 61751:1999

ICS 31.260

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LASER MODULES USED FOR TELECOMMUNICATION RELIABILITY ASSESSMENT (IEC 61751:1998)

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EUROPEAN STANDARD

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Descriptors: Laser modules, telecommunication, reliability

English version

Laser modules used for telecommunication
Reliability assessment
(IEC 61751:1998)

Modules laser utilisés pour les télécommunications
Evaluation de la fiabilité
(CEI 61751:1998)

Lasermodule für Telekommunikationsanwendungen
Zuverläsigkeitsbewertung
(IEC 61751:1998)

This European Standard was approved by CENELEC on 1998-04-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Czech Republic, Denmark, Finland, France, Germany, Greece, Iceland, Ireland, Italy, Luxembourg, Netherlands, Norway, Portugal, Spain, Sweden, Switzerland and United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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Foreword

The text of document 86/115/FDIS, future edition 1 of IEC 61751, prepared by SC 47C, Optoelectronic, display and imaging devices, of IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 61751 on 1998-04-01.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 1999-01-01
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2001-01-01

Annexes designated "normative" are part of the body of the standard.
Annexes designated "informative" are given for information only.
In this standard, annexes A and ZA are normative and annex B is informative.
Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 61751:1998 was approved by CENELEC as a European Standard without any modification.

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

This European Standard incorporates by dated or undated reference, provisions from other publications. These normative references are cited at the appropriate places in the text and the publications are listed hereafter. For dated references, subsequent amendments to or revisions of any of these publications apply to this European Standard only when incorporated in it by amendment or revision. For undated references the latest edition of the publication referred to applies (including amendments).

NOTE: When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

Publication	Year	Title	EN/HD	Year
IEC 60068-2-1	1990	Environmental testing Part 2: Tests Tests A: Cold	EN 60068-2-1	1993
IEC 60068-2-14	1984	Part 2: Tests Test N: Change of temperature	HD 323.2.14 S2[1]	1987
IEC 60747-1	1983	Semiconductor devices Discrete devices and integrated circuits Part 1: General	-	-
+ A3	1996		-	-
IEC 60747-12-2	1995	Part 12: Optoelectronic devices Section 2: Blank detail specification for laser diode modules with pigtail for fibre optic systems and sub-systems	-	-
IEC 60749	1996	Semiconductor devices Mechanical and climatic test methods	-	-
ISO 9000	series	Quality management and quality assurance standards	EN ISO 9000	series
MIL-STD-883	1985	Test Methods and Procedures for Microelectronics	-	-

1) HD 323.2.14 S2 includes A1:1986 to IEC 60068-2-14.